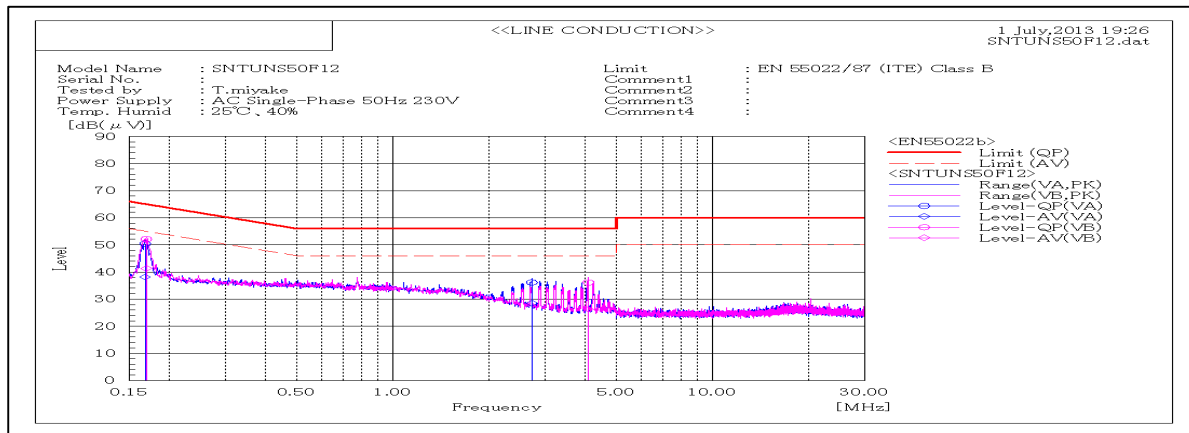
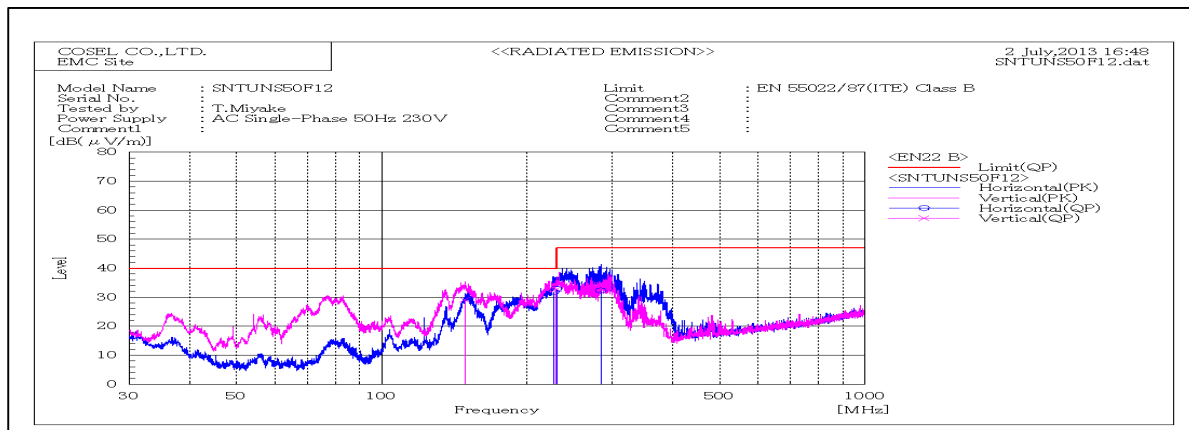


DATA SHEET		Date	19-Jul-13
Model	SNTUNS50F12	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Miyake



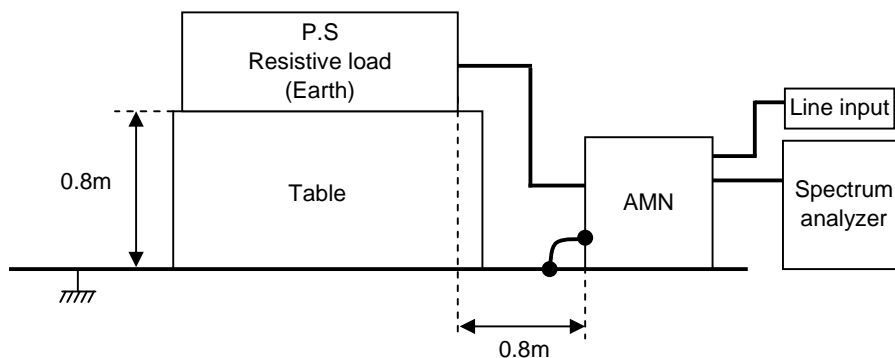
Frequency MHz	Line Phase	Reading dB(μV)		Factor dB	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/ Fail	Remark
		QP	AV		QP	AV	QP	AV	QP	AV		
0.16792	VA	30.2	17.9	20.2	50.4	38.1	65.1	55.1	14.7	17	Pass	
0.16943	VB	32	21.1	20.2	52.2	41.3	65	55	12.8	13.7	Pass	
2.72156	VA	15.7	8.1	20.4	36.1	28.5	56	46	19.9	17.5	Pass	
4.09258	VB	15.7	5.9	20.4	36.1	26.3	56	46	19.9	19.7	Pass	



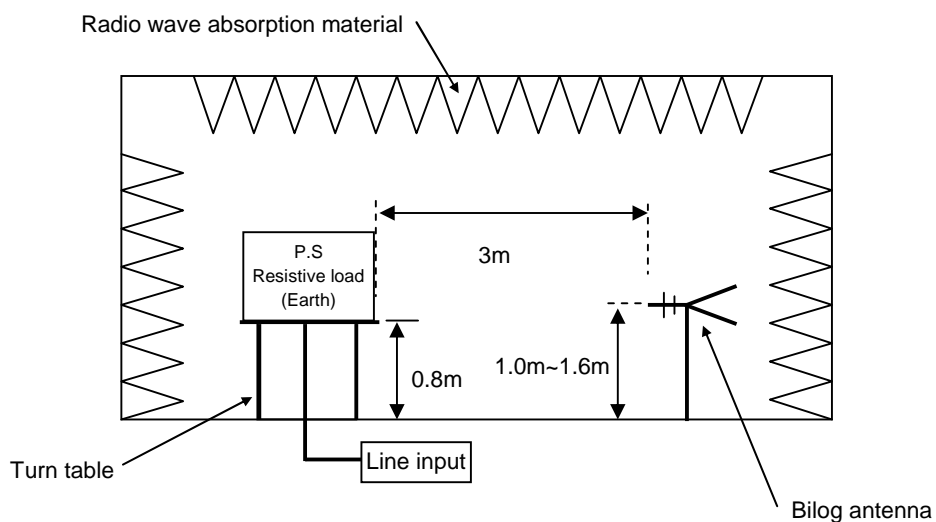
Frequency MHz	Polarization	Stability	Reading dB(μV)		Space Loss dB	Level dB(mW)		Limit dB(mW)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	AV		QP	AV						
148.593	V	Stable	47	-17.9	29.1	40	10.9	40	10.9	Pass	113	94	
226.954	H	Stable	51.5	-19.6	31.9	40	8.1	40	8.1	Pass	147	75	
229.618	V	Stable	47.8	-15.1	32.7	40	7.3	40	7.3	Pass	131	158	
229.876	H	Stable	52.2	-19.3	32.9	40	7.1	40	7.1	Pass	111	80	
283.856	H	Stable	50.3	-18	32.3	47	14.7	47	14.7	Pass	101	248	

DATA SHEET		Date	19-Jul-13
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Miyake

1. Line conduction



2. Radiated emission

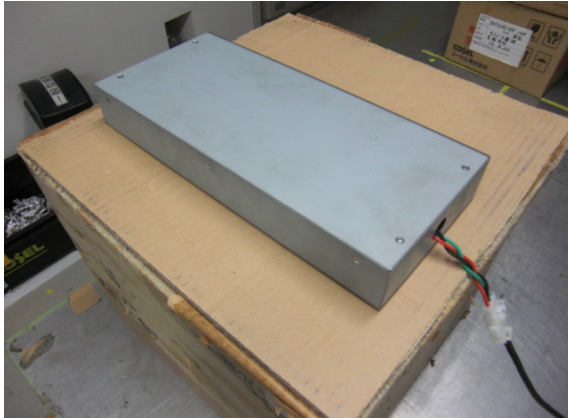


Test:EMI

Model Name: SNTUNS50F Series

○ Photographs of Test Set-Up

LINE CONDUCTION



(A) Outside of a case

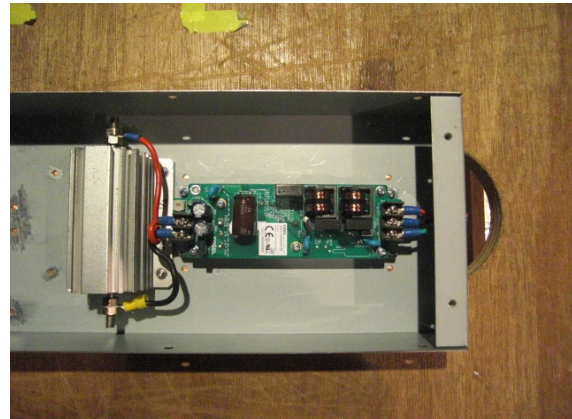


(B) Inside of a case

RADIATED EMISSION



(C) Outside of a case



(D) Inside of a case